AMD Xilinx - XCS20XL-4VQ100C Datasheet

Welcome to E-XFL.COM

Understanding Embedded - FPGAs (Field Programmable Gate Array)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details	
Product Status	Obsolete
Number of LABs/CLBs	400
Number of Logic Elements/Cells	950
Total RAM Bits	12800
Number of I/O	77
Number of Gates	20000
Voltage - Supply	3V ~ 3.6V
Mounting Type	Surface Mount
Operating Temperature	0°C ~ 85°C (TJ)
Package / Case	100-TQFP
Supplier Device Package	100-VQFP (14x14)
Purchase URL	https://www.e-xfl.com/product-detail/xilinx/xcs20xl-4vq100c

Spartan and Spartan-XL devices provide system clock rates exceeding 80 MHz and internal performance in excess of 150 MHz. In addition to the conventional benefit of high volume programmable logic solutions, Spartan series FPGAs also offer on-chip edge-triggered single-port and dual-port RAM, clock enables on all flip-flops, fast carry logic, and many other features.

The Spartan/XL families leverage the highly successful XC4000 architecture with many of that family's features and benefits. Technology advancements have been derived from the XC4000XLA process developments.

Logic Functional Description

The Spartan series uses a standard FPGA structure as shown in Figure 1, page 2. The FPGA consists of an array of configurable logic blocks (CLBs) placed in a matrix of routing channels. The input and output of signals is achieved through a set of input/output blocks (IOBs) forming a ring around the CLBs and routing channels.

- CLBs provide the functional elements for implementing the user's logic.
- IOBs provide the interface between the package pins and internal signal lines.
- Routing channels provide paths to interconnect the inputs and outputs of the CLBs and IOBs.

The functionality of each circuit block is customized during configuration by programming internal static memory cells. The values stored in these memory cells determine the logic functions and interconnections implemented in the FPGA.

Configurable Logic Blocks (CLBs)

The CLBs are used to implement most of the logic in an FPGA. The principal CLB elements are shown in the simplified block diagram in Figure 2. There are three look-up tables (LUT) which are used as logic function generators, two flip-flops and two groups of signal steering multiplexers. There are also some more advanced features provided by the CLB which will be covered in the **Advanced Features Description**, page 13.

Function Generators

Two 16 x 1 memory look-up tables (F-LUT and G-LUT) are used to implement 4-input function generators, each offering unrestricted logic implementation of any Boolean function of up to four independent input signals (F1 to F4 or G1 to G4). Using memory look-up tables the propagation delay is independent of the function implemented.

A third 3-input function generator (H-LUT) can implement any Boolean function of its three inputs. Two of these inputs are controlled by programmable multiplexers (see box "A" of Figure 2). These inputs can come from the F-LUT or G-LUT outputs or from CLB inputs. The third input always comes from a CLB input. The CLB can, therefore, implement certain functions of up to nine inputs, like parity checking. The three LUTs in the CLB can also be combined to do any arbitrarily defined Boolean function of five inputs.

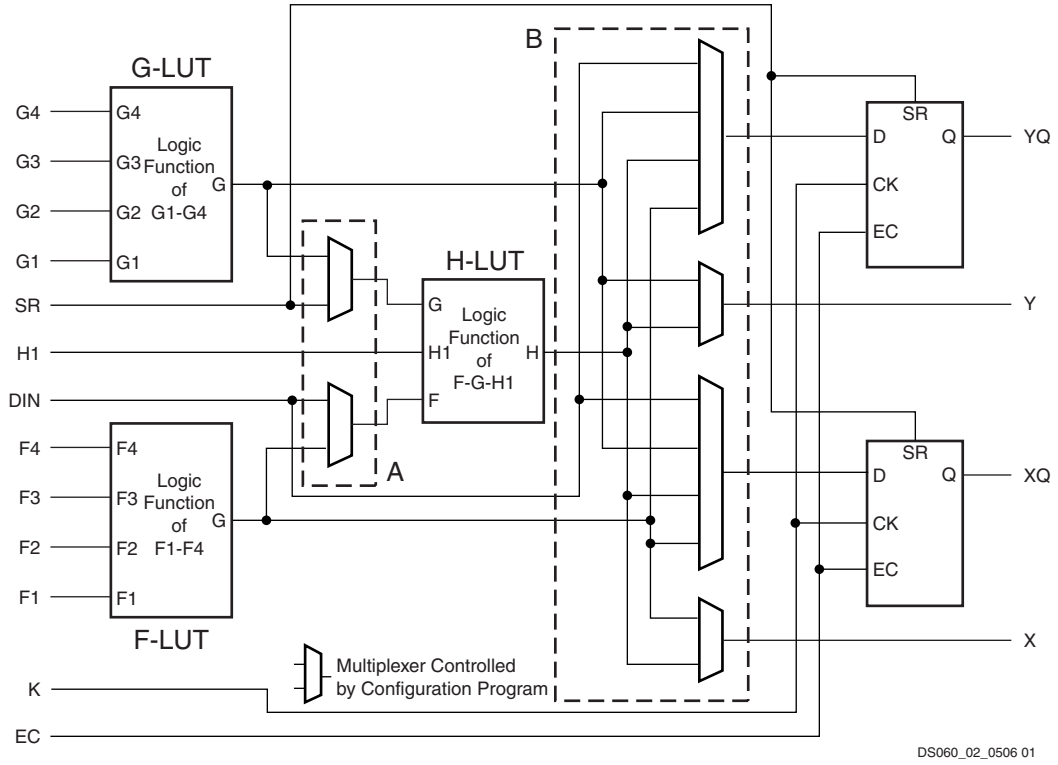


Figure 2: **Spartan/XL Simplified CLB Logic Diagram (some features not shown)**

A CLB can implement any of the following functions:

- Any function of up to four variables, plus any second function of up to four unrelated variables, plus any third function of up to three unrelated variables

  Note: When three separate functions are generated, one of the function outputs must be captured in a flip-flop internal to the CLB. Only two unregistered function generator outputs are available from the CLB.
- Any single function of five variables
- Any function of four variables together with some functions of six variables
- Some functions of up to nine variables.

Implementing wide functions in a single block reduces both the number of blocks required and the delay in the signal path, achieving both increased capacity and speed.

The versatility of the CLB function generators significantly improves system speed. In addition, the design-software tools can deal with each function generator independently. This flexibility improves cell usage.

Flip-Flops

Each CLB contains two flip-flops that can be used to register (store) the function generator outputs. The flip-flops and function generators can also be used independently (see Figure 2). The CLB input DIN can be used as a direct input to either of the two flip-flops. H1 can also drive either flip-flop via the H-LUT with a slight additional delay.

The two flip-flops have common clock (CK), clock enable (EC) and set/reset (SR) inputs. Internally both flip-flops are also controlled by a global initialization signal (GSR) which is described in detail in **Global Signals: GSR and GTS**, page 20.

Latches (Spartan-XL Family Only)

The Spartan-XL family CLB storage elements can also be configured as latches. The two latches have common clock (K) and clock enable (EC) inputs. Functionality of the storage element is described in Table 2.

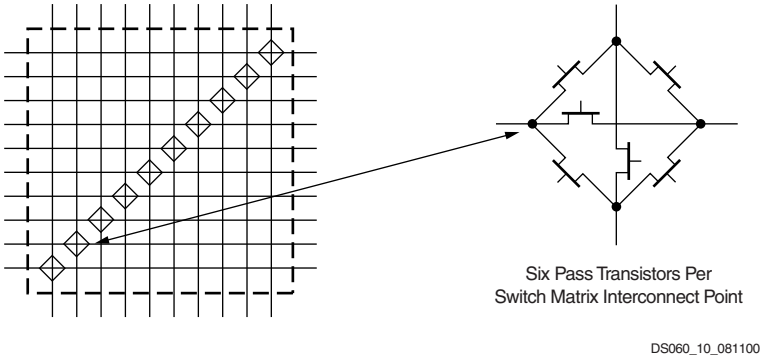


Figure 10: **Programmable Switch Matrix**

Double-Length Lines

The double-length lines consist of a grid of metal segments, each twice as long as the single-length lines: they run past two CLBs before entering a PSM. Double-length lines are grouped in pairs with the PSMs staggered, so that each line goes through a PSM at every other row or column of CLBs (see Figure 8).

There are four vertical and four horizontal double-length lines associated with each CLB. These lines provide faster signal routing over intermediate distances, while retaining routing flexibility.

Longlines

Longlines form a grid of metal interconnect segments that run the entire length or width of the array. Longlines are intended for high fan-out, time-critical signal nets, or nets that are distributed over long distances.

Each Spartan/XL device longline has a programmable splitter switch at its center. This switch can separate the line into two independent routing channels, each running half the width or height of the array.

Routing connectivity of the longlines is shown in Figure 8. The longlines also interface to some 3-state buffers which is described later in **3-State Long Line Drivers**, page 19.

I/O Routing

Spartan/XL devices have additional routing around the IOB ring. This routing is called a VersaRing. The VersaRing facilitates pin-swapping and redesign without affecting board layout. Included are eight double-length lines, and four longlines.

Global Nets and Buffers

The Spartan/XL devices have dedicated global networks. These networks are designed to distribute clocks and other high fanout control signals throughout the devices with minimal skew.

Four vertical longlines in each CLB column are driven exclusively by special global buffers. These longlines are in addition to the vertical longlines used for standard interconnect. In the 5V Spartan devices, the four global lines can be driven by either of two types of global buffers; Primary Global buffers (BUFGP) or Secondary Global buffers (BUFGS). Each of these lines can be accessed by one particular Primary Global buffer, or by any of the Secondary Global buffers, as shown in Figure 11. In the 3V Spartan-XL devices, the four global lines can be driven by any of the eight Global Low-Skew Buffers (BUFGLS). The clock pins of every CLB and IOB can also be sourced from local interconnect.

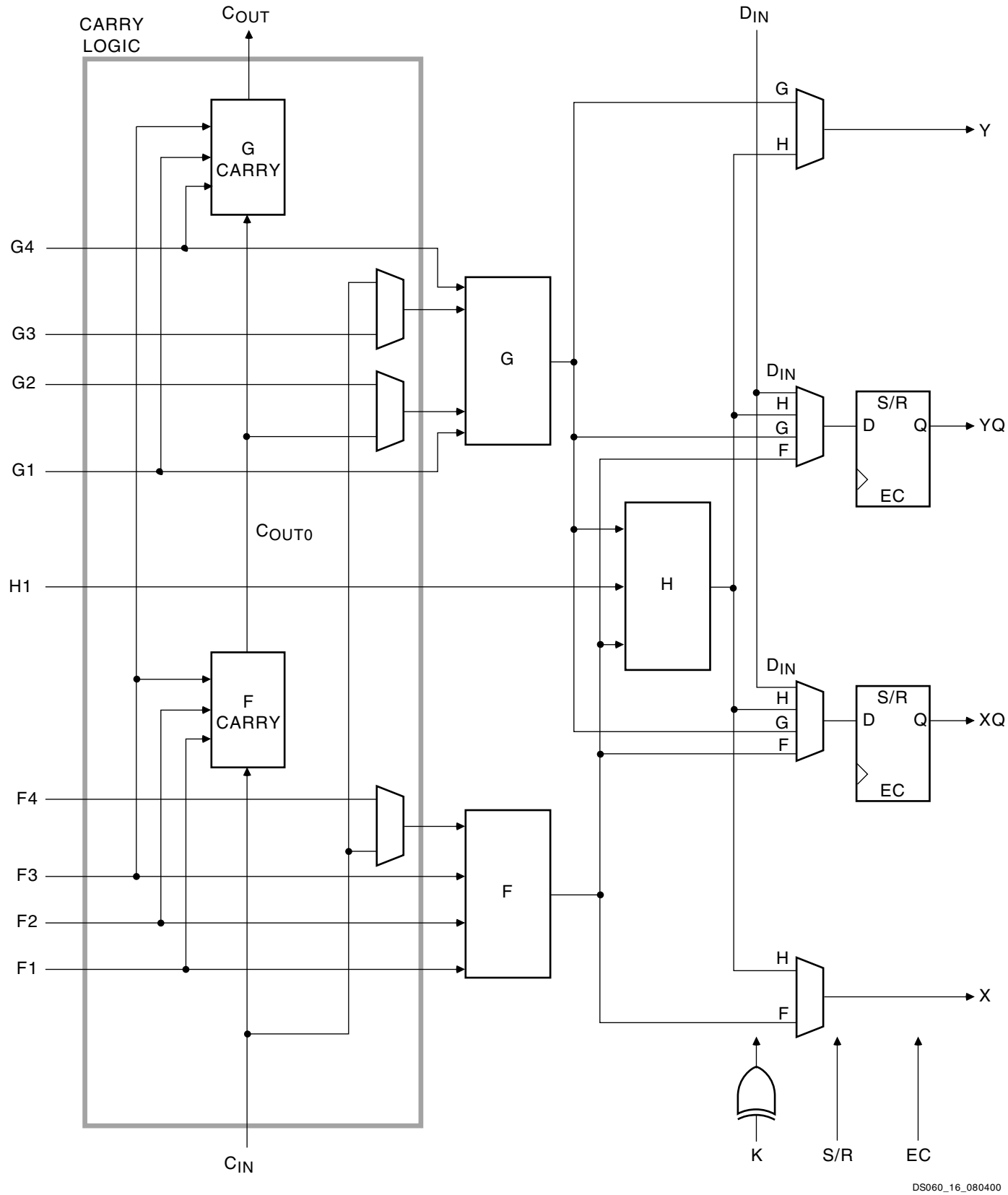


Figure 16: **Fast Carry Logic in Spartan/XL CLB**

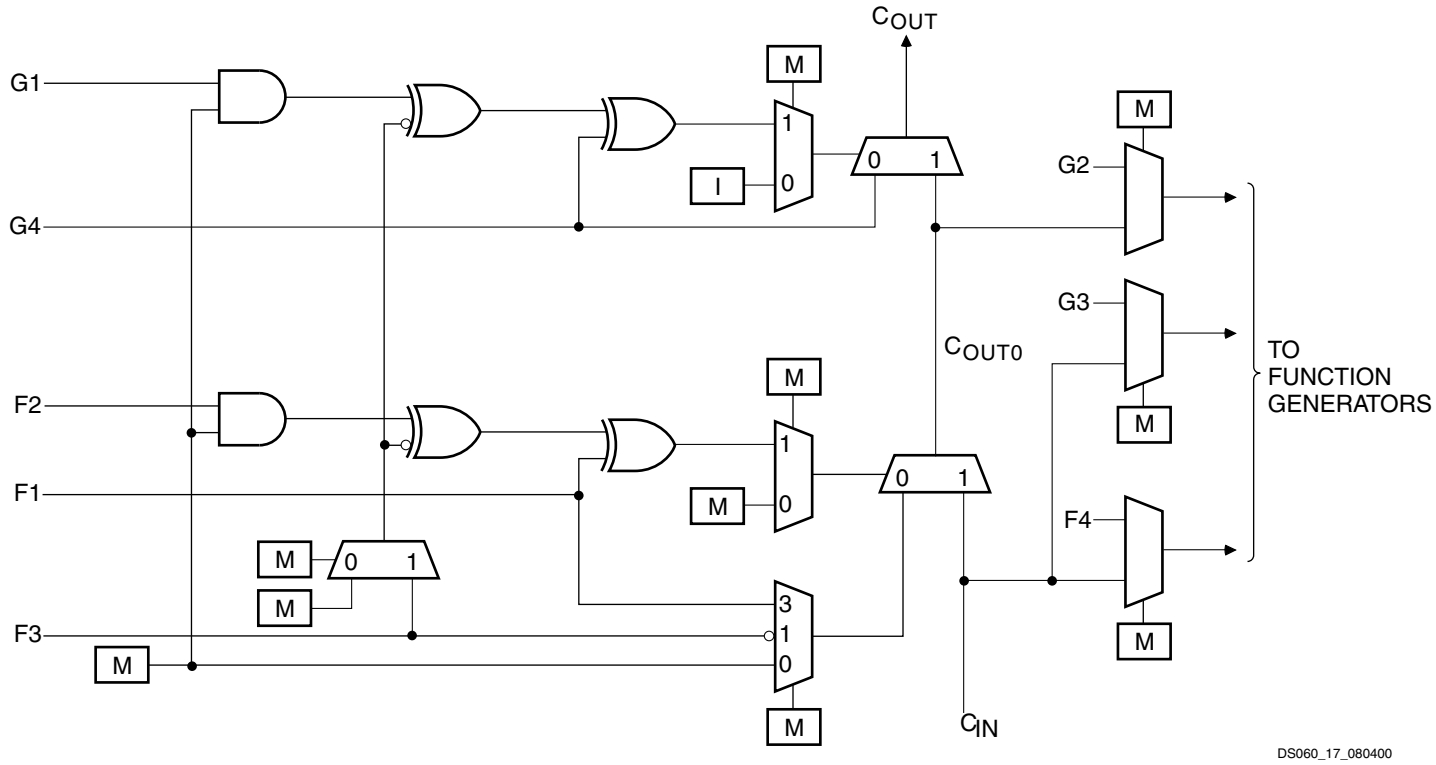


Figure 17: **Detail of Spartan/XL Dedicated Carry Logic**

3-State Long Line Drivers

A pair of 3-state buffers is associated with each CLB in the array. These 3-state buffers (BUFT) can be used to drive signals onto the nearest horizontal longlines above and below the CLB. They can therefore be used to implement multiplexed or bidirectional buses on the horizontal longlines, saving logic resources.

There is a weak keeper at each end of these two horizontal longlines. This circuit prevents undefined floating levels. However, it is overridden by any driver.

The buffer enable is an active High 3-state (i.e., an active Low enable), as shown in Table 11.

Three-State Buffer Example

Figure 18 shows how to use the 3-state buffers to implement a multiplexer. The selection is accomplished by the buffer 3-state signal.

Pay particular attention to the polarity of the T pin when using these buffers in a design. Active High 3-state (T) is identical to an active Low output enable, as shown in Table 11.

Table 11: **Three-State Buffer Functionality**

IN	T	OUT
X	1	Z
IN	0	IN

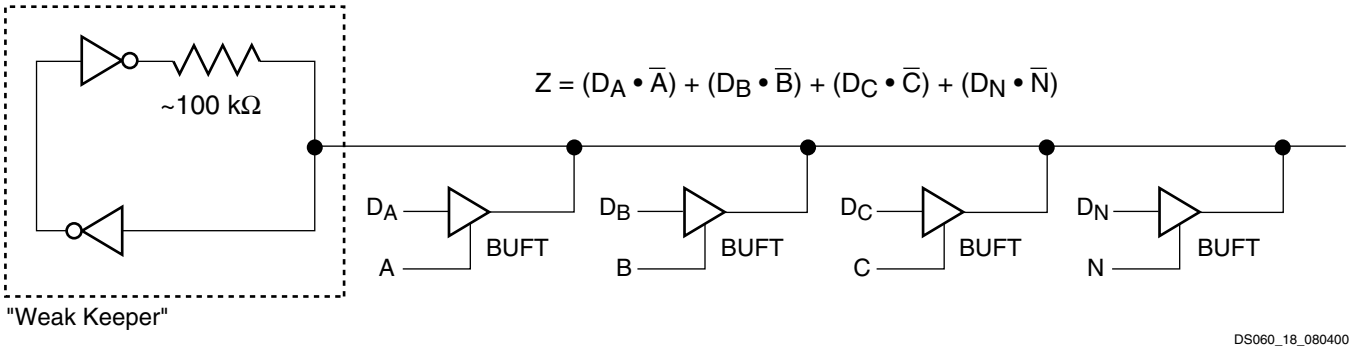


Figure 18: **3-state Buffers Implement a Multiplexer**

Table 12: **Boundary Scan Instructions**

Instruction			Test Selected	TDO Source	I/O Data Source
I2	I1	I0			
0	0	0	EXTEST	DR	DR
0	0	1	SAMPLE/ PRELOAD	DR	Pin/Logic
0	1	0	USER 1	BSCAN. TDO1	User Logic
0	1	1	USER 2	BSCAN. TDO2	User Logic
1	0	0	READBACK	Readback Data	Pin/Logic
1	0	1	CONFIGURE	DOUT	Disabled
1	1	0	IDCODE (Spartan-XL only)	IDCODE Register	-
1	1	1	BYPASS	Bypass Register	-

Bit Sequence

The bit sequence within each IOB is: In, Out, 3-state. The input-only pins contribute only the In bit to the boundary scan I/O data register, while the output-only pins contributes all three bits.

The first two bits in the I/O data register are TDO.T and TDO.O, which can be used for the capture of internal signals. The final bit is BSCANT.UPD, which can be used to drive an internal net. These locations are primarily used by Xilinx for internal testing.

From a cavity-up view of the chip (as shown in the FPGA Editor), starting in the upper right chip corner, the boundary scan data-register bits are ordered as shown in Figure 21. The device-specific pinout tables for the Spartan/XL devices include the boundary scan locations for each IOB pin.

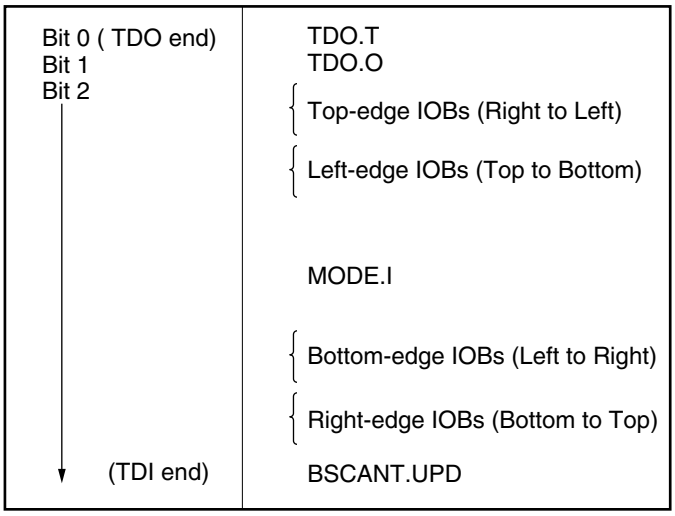


Figure 21: **Boundary Scan Bit Sequence**

BSDL (Boundary Scan Description Language) files for Spartan/XL devices are available on the Xilinx website in the File Download area. Note that the 5V Spartan devices and 3V Spartan-XL devices have different BSDL files.

Including Boundary Scan in a Design

If boundary scan is only to be used during configuration, no special elements need be included in the schematic or HDL code. In this case, the special boundary scan pins TDI, TMS, TCK and TDO can be used for user functions after configuration.

To indicate that boundary scan remain enabled after configuration, place the BSCAN library symbol and connect the TDI, TMS, TCK and TDO pad symbols to the appropriate pins, as shown in Figure 22.

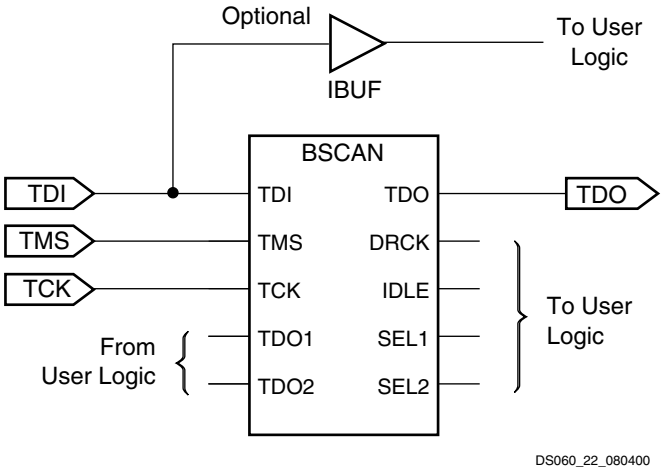
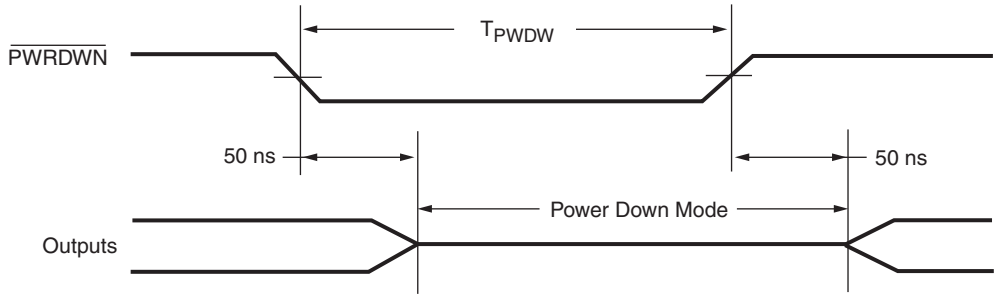


Figure 22: **Boundary Scan Example**



Description	Symbol	Min
Power Down Time	T_{PWD}	50 ns
Power Down Pulse Width	T_{PWDW}	50 ns

DS060_23_041901

Figure 23: **$\overline{\text{PWRDWN}}$ Pulse Timing**

Power-down retains the configuration, but loses all data stored in the device flip-flops. All inputs are interpreted as Low, but the internal combinatorial logic is fully functional. Make sure that the combination of all inputs Low and all flip-flops set or reset in your design will not generate internal oscillations, or create permanent bus contention by activating internal bus drivers with conflicting data onto the same long line.

During configuration, the $\overline{\text{PWRDWN}}$ pin must be High. If the Power Down state is entered before or during configuration, the device will restart configuration once the $\overline{\text{PWRDWN}}$ signal is removed. Note that the configuration pins are affected by Power Down and may not reflect their normal function. If there is an external pull-up resistor on the DONE pin, it will be High during Power Down even if the device is not yet configured. Similarly, if $\overline{\text{PWRDWN}}$ is asserted before configuration is completed, the $\overline{\text{INIT}}$ pin will not indicate status information.

Note that the $\overline{\text{PWRDWN}}$ pin is not part of the Boundary Scan chain. Therefore, the Spartan-XL family has a separate set of BSDL files than the 5V Spartan family. Boundary scan logic is not usable during Power Down.

Configuration and Test

Configuration is the process of loading design-specific programming data into one or more FPGAs to define the functional operation of the internal blocks and their interconnections. This is somewhat like loading the command registers of a programmable peripheral chip. Spartan/XL devices use several hundred bits of configuration data per CLB and its associated interconnects. Each configuration bit defines the state of a static memory cell that controls either a function look-up table bit, a multiplexer input, or an interconnect pass transistor. The Xilinx development system translates the design into a netlist file. It automatically partitions, places and routes the logic and generates the configuration data in PROM format.

Configuration Mode Control

5V Spartan devices have two configuration modes.

- MODE = 1 sets Slave Serial mode
- MODE = 0 sets Master Serial mode

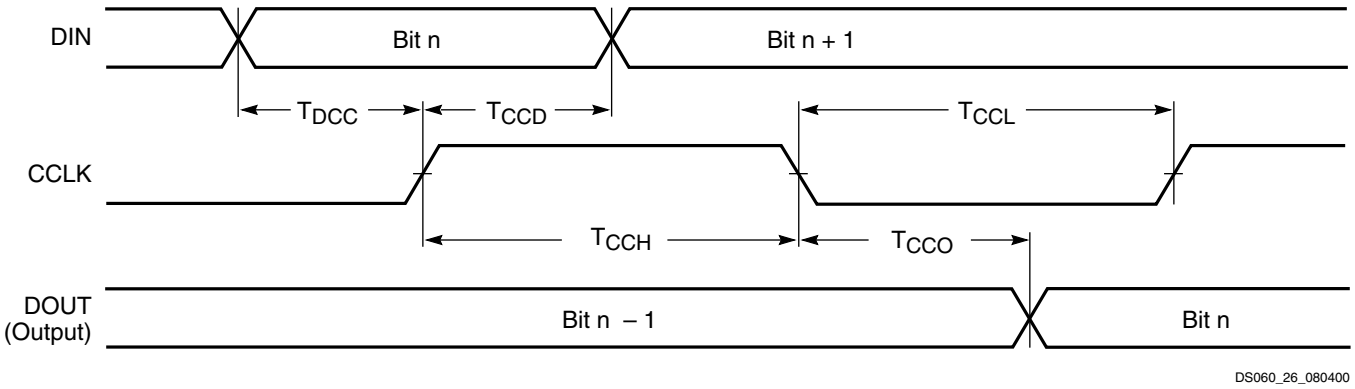
3V Spartan-XL devices have three configuration modes.

- M1/M0 = 11 sets Slave Serial mode
- M1/M0 = 10 sets Master Serial mode
- M1/M0 = 0X sets Express mode

In addition to these modes, the device can be configured through the Boundary Scan logic (See "Configuration Through the Boundary Scan Pins" on page 37.).

The Mode pins are sampled prior to starting configuration to determine the configuration mode. After configuration, these pin are unused. The Mode pins have a weak pull-up resistor turned on during configuration. With the Mode pins High, Slave Serial mode is selected, which is the most popular configuration mode. Therefore, for the most common configuration mode, the Mode pins can be left unconnected. If the Master Serial mode is desired, the MODE/M0 pin should be connected directly to GND, or through a pull-down resistor of 1 KΩ or less.

During configuration, some of the I/O pins are used temporarily for the configuration process. All pins used during con-



Symbol		Description	Min	Max	Units
T_{DCC}	CCLK	DIN setup	20	-	ns
T_{CCD}		DIN hold	0	-	ns
T_{CCO}		DIN to DOUT	-	30	ns
T_{CCH}		High time	40	-	ns
T_{CCL}		Low time	40	-	ns
F_{CC}		Frequency	-	12.5	MHz

Notes:
1. Configuration must be delayed until the $\overline{INIT}$ pins of all daisy-chained FPGAs are High.

Figure 26: **Slave Serial Mode Programming Switching Characteristics**

Express Mode (Spartan-XL Family Only)

Express mode is similar to Slave Serial mode, except that data is processed one byte per CCLK cycle instead of one bit per CCLK cycle. An external source is used to drive CCLK, while byte-wide data is loaded directly into the configuration data shift registers (Figure 27). A CCLK frequency of 1 MHz is equivalent to a 8 MHz serial rate, because eight bits of configuration data are loaded per CCLK cycle. Express mode does not support CRC error checking, but does support constant-field error checking. A length count is not used in Express mode.

Express mode must be specified as an option to the development system. The Express mode bitstream is not compatible with the other configuration modes (see Table 16, page 32.) Express mode is selected by a <0X> on the Mode pins (M1, M0).

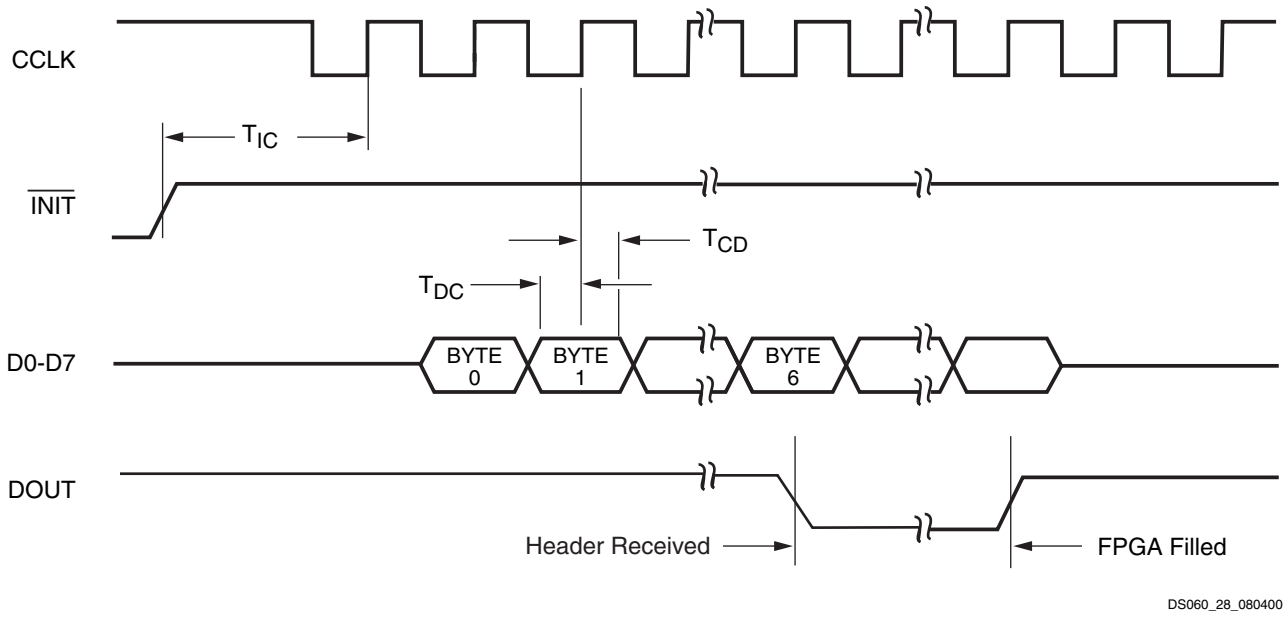
The first byte of parallel configuration data must be available at the D inputs of the FPGA a short setup time before the second rising CCLK edge. Subsequent data bytes are clocked in on each consecutive rising CCLK edge (Figure 28).

Pseudo Daisy Chain

Multiple devices with different configurations can be configured in a pseudo daisy chain provided that all of the devices are in Express mode. Concatenated bitstreams are used to configure the chain of Express mode devices so that each device receives a separate header. CCLK pins are tied together and D0-D7 pins are tied together for all devices along the chain. A status signal is passed from DOUT to CS1 of successive devices along the chain. Frame data is accepted only when CS1 is High and the device's configuration memory is not already full. The lead device in the chain has its CS1 input tied High (or floating, since there is an internal pull-up). The status pin DOUT is pulled Low after the header is received, and remains Low until the device's configuration memory is full. DOUT is then pulled High to signal the next device in the chain to accept the next header and configuration data on the D0-D7 bus.

The DONE pins of all devices in the chain should be tied together, with one or more active internal pull-ups. If a large number of devices are included in the chain, deactivate some of the internal pull-ups, since the Low-driving DONE pin of the last device in the chain must sink the current from all pull-ups in the chain. The DONE pull-up is activated by default. It can be deactivated using a development system option.

The requirement that all DONE pins in a daisy chain be wired together applies only to Express mode, and only if all devices in the chain are to become active simultaneously. All Spartan-XL devices in Express mode are synchronized



Symbol		Description	Min	Max	Units
T_{IC}	CCLK	$\overline{INIT}$ (High) setup time	5	-	µs
T_{DC}		D0-D7 setup time	20	-	ns
T_{CD}		D0-D7 hold time	0	-	ns
T_{CCH}		CCLK High time	45	-	ns
T_{CCL}		CCLK Low time	45	-	ns
F_{CC}		CCLK Frequency	-	10	MHz

Notes:
1. If not driven by the preceding DOUT, CS1 *must* remain High until the device is fully configured.

Figure 28: **Express Mode Programming Switching Characteristics**

Setting CCLK Frequency

In Master mode, CCLK can be generated in either of two frequencies. In the default slow mode, the frequency ranges from 0.5 MHz to 1.25 MHz for Spartan/XL devices. In fast CCLK mode, the frequency ranges from 4 MHz to 10 MHz for Spartan/XL devices. The frequency is changed to fast by an option when running the bitstream generation software.

Data Stream Format

The data stream ("bitstream") format is identical for both serial configuration modes, but different for the Spartan-XL family Express mode. In Express mode, the device becomes active when DONE goes High, therefore no length count is required. Additionally, CRC error checking is not supported in Express mode. The data stream format is shown in Table 16. Bit-serial data is read from left to right. Express mode data is shown with D0 at the left and D7 at the right.

The configuration data stream begins with a string of eight ones, a preamble code, followed by a 24-bit length count and a separator field of ones (or 24 fill bits, in Spartan-XL family Express mode). This header is followed by the actual configuration data in frames. The length and number of frames depends on the device type (see Table 17). Each frame begins with a start field and ends with an error check. In serial modes, a postamble code is required to signal the end of data for a single device. In all cases, additional start-up bytes of data are required to provide four clocks for the startup sequence at the end of configuration. Long daisy chains require additional startup bytes to shift the last data through the chain. All start-up bytes are "don't cares".

Readback Switching Characteristics Guidelines

The following guidelines reflect worst-case values over the recommended operating conditions.

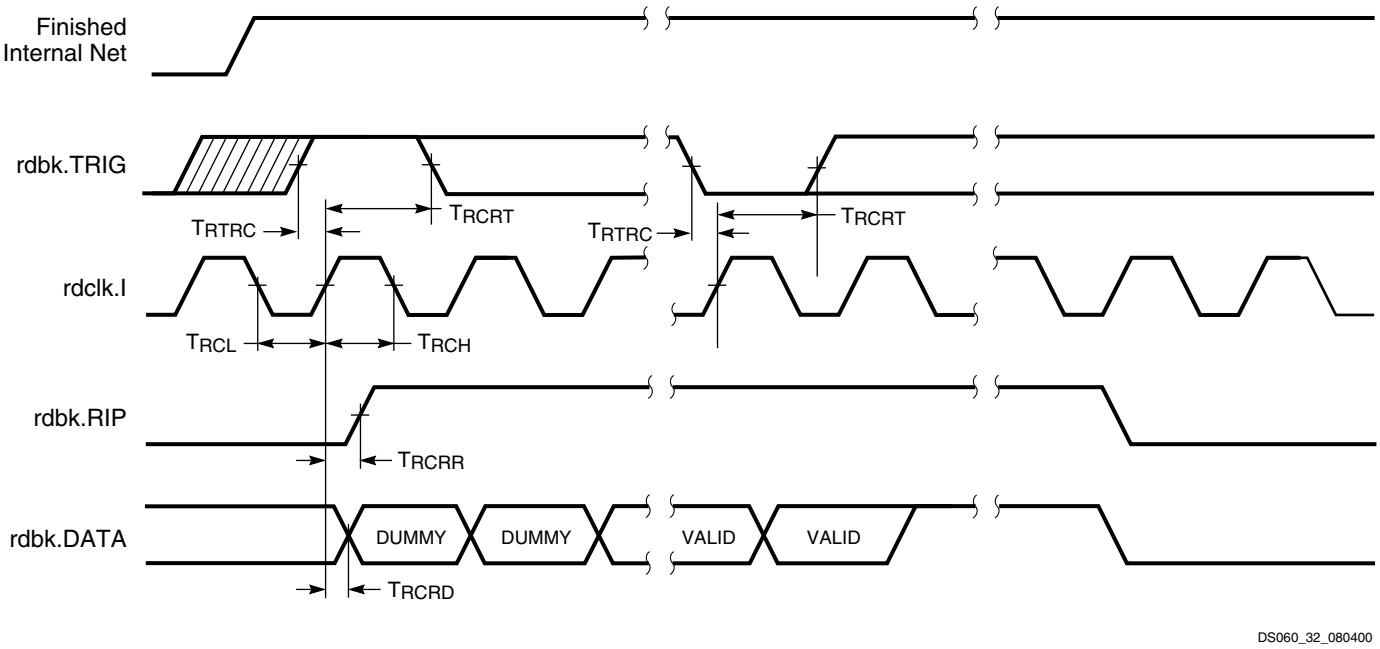


Figure 33: **Spartan and Spartan-XL Readback Timing Diagram**

Spartan and Spartan-XL Readback Switching Characteristics

Symbol		Description	Min	Max	Units
T_{RTRC}	rdbk.TRIG	rdbk.TRIG setup to initiate and abort Readback	200	-	ns
T_{RCRT}		rdbk.TRIG hold to initiate and abort Readback	50	-	ns
T_{RCRD}	rdclk.I	rdbk.DATA delay	-	250	ns
T_{RCRR}		rdbk.RIP delay	-	250	ns
T_{RCH}		High time	250	500	ns
T_{RCL}		Low time	250	500	ns

Notes:
1. Timing parameters apply to all speed grades.
2. If rdbk.TRIG is High prior to Finished, Finished will trigger the first Readback.

Spartan Family DC Characteristics Over Operating Conditions

Symbol	Description		Min	Max	Units
V_{OH}	High-level output voltage @ I_{OH} = –4.0 mA, V_{CC} min	TTL outputs	2.4	-	V
	High-level output voltage @ I_{OH} = –1.0 mA, V_{CC} min	CMOS outputs	V_{CC} – 0.5	-	V
V_{OL}	Low-level output voltage @ I_{OL} = 12.0 mA, V_{CC} min(1)	TTL outputs	-	0.4	V
		CMOS outputs	-	0.4	V
V_{DR}	Data retention supply voltage (below which configuration data may be lost)		3.0	-	V
I_{CCO}	Quiescent FPGA supply current(2)	Commercial	-	3.0	mA
		Industrial	-	6.0	mA
I_L	Input or output leakage current		–10	+10	µA
C_{IN}	Input capacitance (sample tested)		-	10	pF
I_{RPU}	Pad pull-up (when selected) @ V_{IN} = 0V (sample tested)		0.02	0.25	mA
I_{RPD}	Pad pull-down (when selected) @ V_{IN} = 5V (sample tested)		0.02	-	mA

Notes:
1. With 50% of the outputs simultaneously sinking 12 mA, up to a maximum of 64 pins.
2. With no output current loads, no active input pull-up resistors, all package pins at V_{CC} or GND, and the FPGA configured with a Tie option.

Spartan Family Global Buffer Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values where one global clock input drives one vertical clock line in each accessible column, and where all accessible IOB and CLB flip-flops are clocked by the global clock net.

When fewer vertical clock lines are connected, the clock distribution is faster; when multiple clock lines per column are driven from the same global clock, the delay is longer. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature).

Symbol	Description	Device	Speed Grade		Units
			-4	-3	
			Max	Max	
T_{PG}	From pad through Primary buffer, to any clock K	XCS05	2.0	4.0	ns
		XCS10	2.4	4.3	ns
		XCS20	2.8	5.4	ns
		XCS30	3.2	5.8	ns
		XCS40	3.5	6.4	ns
T_{SG}	From pad through Secondary buffer, to any clock K	XCS05	2.5	4.4	ns
		XCS10	2.9	4.7	ns
		XCS20	3.3	5.8	ns
		XCS30	3.6	6.2	ns
		XCS40	3.9	6.7	ns

Spartan Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade				Units
		-4		-3		
		Min	Max	Min	Max	
Clocks						
T_{CH}	Clock High time	3.0	-	4.0	-	ns
T_{CL}	Clock Low time	3.0	-	4.0	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.2	-	1.6	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	2.0	-	2.7	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.7	-	2.2	ns
CLB Fast Carry Logic						
T_{OPCY}	Operand inputs (F1, F2, G1, G4) to C_{OUT}	-	1.7	-	2.1	ns
T_{ASCY}	Add/Subtract input (F3) to C_{OUT}	-	2.8	-	3.7	ns
T_{INCY}	Initialization inputs (F1, F3) to C_{OUT}	-	1.2	-	1.4	ns
T_{SUM}	C_{IN} through function generators to X/Y outputs	-	2.0	-	2.6	ns
T_{BYP}	C_{IN} to C_{OUT}, bypass function generators	-	0.5	-	0.6	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop outputs Q	-	2.1	-	2.8	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	1.8	-	2.4	-	ns
T_{IHCK}	F/G inputs via H	2.9	-	3.9	-	ns
T_{HH1CK}	C inputs via H1 through H	2.3	-	3.3	-	ns
T_{DICK}	C inputs via DIN	1.3	-	2.0	-	ns
T_{ECCK}	C inputs via EC	2.0	-	2.6	-	ns
T_{RCK}	C inputs via S/R, going Low (inactive)	2.5	-	4.0	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	3.0	-	4.0	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	3.0	-	4.0	ns
Global Set/Reset						
T_{MRW}	Minimum GSR pulse width	11.5	-	13.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 50 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	166	-	125	MHz

Spartan Family Pin-to-Pin Output Parameter Guidelines

All devices are 100% functionally tested. Pin-to-pin timing parameters are derived from measuring external and internal test patterns and are guaranteed over worst-case operating conditions (supply voltage and junction temperature). Listed below are representative values for typical pin locations and normal clock loading. For more specific, more precise, and worst-case guaranteed data, reflecting the actual routing structure, use the values provided by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. These path delays, provided as a guideline, have been extracted from the static timing analyzer report.

Spartan Family Output Flip-Flop, Clock-to-Out

Symbol	Description	Device	Speed Grade		Units
			-4	-3	
			Max	Max	
Global Primary Clock to TTL Output using OFF					
T_{ICKOF}	Fast	XCS05	5.3	8.7	ns
		XCS10	5.7	9.1	ns
		XCS20	6.1	9.3	ns
		XCS30	6.5	9.4	ns
		XCS40	6.8	10.2	ns
T_{ICKO}	Slew-rate limited	XCS05	9.0	11.5	ns
		XCS10	9.4	12.0	ns
		XCS20	9.8	12.2	ns
		XCS30	10.2	12.8	ns
		XCS40	10.5	12.8	ns
Global Secondary Clock to TTL Output using OFF					
T_{ICKSOF}	Fast	XCS05	5.8	9.2	ns
		XCS10	6.2	9.6	ns
		XCS20	6.6	9.8	ns
		XCS30	7.0	9.9	ns
		XCS40	7.3	10.7	ns
T_{ICKSO}	Slew-rate limited	XCS05	9.5	12.0	ns
		XCS10	9.9	12.5	ns
		XCS20	10.3	12.7	ns
		XCS30	10.7	13.2	ns
		XCS40	11.0	14.3	ns
Delay Adder for CMOS Outputs Option					
T_{CMOSOF}	Fast	All devices	0.8	1.0	ns
T_{CMOSO}	Slew-rate limited	All devices	1.5	2.0	ns

Notes:
1. Listed above are representative values where one global clock input drives one vertical clock line in each accessible column,and where all accessible IOB and CLB flip-flops are clocked by the global clock net.
2. Output timing is measured at ~50% V_{CC} threshold with 50 pF external capacitive load. For different loads, see Figure 34.
3. OFF = Output Flip-Flop

Spartan-XL Family Detailed Specifications

Definition of Terms

In the following tables, some specifications may be designated as Advance or Preliminary. These terms are defined as follows:

Advance: Initial estimates based on simulation and/or extrapolation from other speed grades, devices, or device families. Values are subject to change. Use as estimates, not for production.
Preliminary: Based on preliminary characterization. Further changes are not expected.
Unmarked: Specifications not identified as either Advance or Preliminary are to be considered Final.

Notwithstanding the definition of the above terms, all specifications are subject to change without notice.

Except for pin-to-pin input and output parameters, the AC parameter delay specifications included in this document are derived from measuring internal test patterns. All specifications are representative of worst-case supply voltage and junction temperature conditions. The parameters included are common to popular designs and typical applications.

Spartan-XL Family Absolute Maximum Ratings(1)

Symbol	Description		Value	Units
V_{CC}	Supply voltage relative to GND		–0.5 to 4.0	V
V_{IN}	Input voltage relative to GND	5V Tolerant I/O Checked(2, 3)	–0.5 to 5.5	V
		Not 5V Tolerant I/Os(4, 5)	–0.5 to V_{CC} + 0.5	V
V_{TS}	Voltage applied to 3-state output	5V Tolerant I/O Checked(2, 3)	–0.5 to 5.5	V
		Not 5V Tolerant I/Os(4, 5)	–0.5 to V_{CC} + 0.5	V
T_{STG}	Storage temperature (ambient)		–65 to +150	°C
T_J	Junction temperature	Plastic packages	+125	°C

Notes:
1. Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those listed under Operating Conditions is not implied. Exposure to Absolute Maximum Ratings conditions for extended periods of time may affect device reliability.
2. With 5V Tolerant I/Os selected, the Maximum DC overshoot must be limited to either +5.5V or 10 mA and undershoot (below GND) must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
3. With 5V Tolerant I/Os selected, the Maximum AC (during transitions) conditions are as follows; the device pins may undershoot to –2.0V or overshoot to + 7.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
4. Without 5V Tolerant I/Os selected, the Maximum DC overshoot or undershoot must be limited to either 0.5V or 10 mA, whichever is easier to achieve.
5. Without 5V Tolerant I/Os selected, the Maximum AC conditions are as follows; the device pins may undershoot to –2.0V or overshoot to V_{CC} + 2.0V, provided this overshoot or undershoot lasts no more than 11 ns with a forcing current no greater than 100 mA.
6. For soldering guidelines, see the Package Information on the Xilinx website.

Spartan-XL Family Recommended Operating Conditions

Symbol	Description		Min	Max	Units
V_{CC}	Supply voltage relative to GND, T_J = 0°C to +85°C	Commercial	3.0	3.6	V
	Supply voltage relative to GND, T_J = –40°C to +100°C(1)	Industrial	3.0	3.6	V
V_{IH}	High-level input voltage(2)		50% of V_{CC}	5.5	V
V_{IL}	Low-level input voltage(2)		0	30% of V_{CC}	V
T_{IN}	Input signal transition time		-	250	ns

Notes:
1. At junction temperatures above those listed as Operating Conditions, all delay parameters increase by 0.35% per °C.
2. Input and output measurement threshold is ~50% of V_{CC}.

Spartan-XL Family CLB Switching Characteristic Guidelines

All devices are 100% functionally tested. Internal timing parameters are derived from measuring internal test patterns. Listed below are representative values. For more specific, more precise, and worst-case guaranteed data, use the values reported by the static timing analyzer (TRCE in the Xilinx Development System) and back-annotated to the simulation netlist. All timing parameters assume worst-case operating conditions (supply voltage and junction temperature). Values apply to all Spartan-XL devices and expressed in nanoseconds unless otherwise noted.

Symbol	Description	Speed Grade				Units
		-5		-4		
		Min	Max	Min	Max	
Clocks						
T_{CH}	Clock High time	2.0	-	2.3	-	ns
T_{CL}	Clock Low time	2.0	-	2.3	-	ns
Combinatorial Delays						
T_{ILO}	F/G inputs to X/Y outputs	-	1.0	-	1.1	ns
T_{IHO}	F/G inputs via H to X/Y outputs	-	1.7	-	2.0	ns
T_{ITO}	F/G inputs via transparent latch to Q outputs	-	1.5	-	1.8	ns
T_{HH1O}	C inputs via H1 via H to X/Y outputs	-	1.5	-	1.8	ns
Sequential Delays						
T_{CKO}	Clock K to Flip-Flop or latch outputs Q	-	1.2	-	1.4	ns
Setup Time before Clock K						
T_{ICK}	F/G inputs	0.6	-	0.7	-	ns
T_{IHCK}	F/G inputs via H	1.3	-	1.6	-	ns
Hold Time after Clock K						
	All Hold times, all devices	0.0	-	0.0	-	ns
Set/Reset Direct						
T_{RPW}	Width (High)	2.5	-	2.8	-	ns
T_{RIO}	Delay from C inputs via S/R, going High to Q	-	2.3	-	2.7	ns
Global Set/Reset						
T_{MRW}	Minimum GSR Pulse Width	10.5	-	11.5	-	ns
T_{MRQ}	Delay from GSR input to any Q	See page 60 for T_{RRI} values per device.				
F_{TOG}	Toggle Frequency (MHz) (for export control purposes)	-	250	-	217	MHz

Pin Descriptions

There are three types of pins in the Spartan/XL devices:

- Permanently dedicated pins
- User I/O pins that can have special functions
- Unrestricted user-programmable I/O pins.

Before and during configuration, all outputs not used for the configuration process are 3-stated with the I/O pull-up resistor network activated. After configuration, if an IOB is unused it is configured as an input with the I/O pull-up resistor network remaining activated.

Any user I/O can be configured to drive the Global Set/Reset net GSR or the global three-state net GTS. See **Global Signals: GSR and GTS**, page 20 for more information.

Device pins for Spartan/XL devices are described in Table 18.

Some Spartan-XL devices are available in Pb-free package options. The Pb-free package options have the same pinouts as the standard package options.

Table 18: **Pin Descriptions**

Pin Name	I/O During Config.	I/O After Config.	Pin Description
Permanently Dedicated Pins			
V_{CC}	X	X	Eight or more (depending on package) connections to the nominal +5V supply voltage (+3.3V for Spartan-XL devices). All must be connected, and each must be decoupled with a 0.01 –0.1 µF capacitor to Ground.
GND	X	X	Eight or more (depending on package type) connections to Ground. All must be connected.
CCLK	I or O	I	During configuration, Configuration Clock (CCLK) is an output in Master mode and is an input in Slave mode. After configuration, CCLK has a weak pull-up resistor and can be selected as the Readback Clock. There is no CCLK High or Low time restriction on Spartan/XL devices, except during Readback. See **Violating the Maximum High and Low Time Specification for the Readback Clock**, page 39 for an explanation of this exception.
DONE	I/O	O	DONE is a bidirectional signal with an optional internal pull-up resistor. As an open-drain output, it indicates the completion of the configuration process. As an input, a Low level on DONE can be configured to delay the global logic initialization and the enabling of outputs. The optional pull-up resistor is selected as an option in the program that creates the configuration bitstream. The resistor is included by default.
$\overline{\text{PROGRAM}}$	I	I	$\overline{\text{PROGRAM}}$ is an active Low input that forces the FPGA to clear its configuration memory. It is used to initiate a configuration cycle. When $\overline{\text{PROGRAM}}$ goes High, the FPGA finishes the current clear cycle and executes another complete clear cycle, before it goes into a WAIT state and releases $\overline{\text{INIT}}$. The $\overline{\text{PROGRAM}}$ pin has a permanent weak pull-up, so it need not be externally pulled up to VCC.
MODE (Spartan) M0, M1 (Spartan-XL)	I	X	The Mode input(s) are sampled after $\overline{\text{INIT}}$ goes High to determine the configuration mode to be used. During configuration, these pins have a weak pull-up resistor. For the most popular configuration mode, Slave Serial, the mode pins can be left unconnected. For Master Serial mode, connect the Mode/M0 pin directly to system ground.

Table 18: **Pin Descriptions *(Continued)***

Pin Name	I/O During Config.	I/O After Config.	Pin Description
$\overline{\text{PWRDWN}}$	I	I	$\overline{\text{PWRDWN}}$ is an active Low input that forces the FPGA into the Power Down state and reduces power consumption. When $\overline{\text{PWRDWN}}$ is Low, the FPGA disables all I/O and initializes all flip-flops. All inputs are interpreted as Low independent of their actual level. VCC must be maintained, and the configuration data is maintained. $\overline{\text{PWRDWN}}$ halts configuration if asserted before or during configuration, and re-starts configuration when removed. When $\overline{\text{PWRDWN}}$ returns High, the FPGA becomes operational by first enabling the inputs and flip-flops and then enabling the outputs. $\overline{\text{PWRDWN}}$ has a default internal pull-up resistor.
User I/O Pins That Can Have Special Functions			
TDO	O	O	If boundary scan is used, this pin is the Test Data Output. If boundary scan is not used, this pin is a 3-state output without a register, after configuration is completed. To use this pin, place the library component TDO instead of the usual pad symbol. An output buffer must still be used.
TDI, TCK, TMS	I	I/O or I (JTAG)	If boundary scan is used, these pins are Test Data In, Test Clock, and Test Mode Select inputs respectively. They come directly from the pads, bypassing the IOBs. These pins can also be used as inputs to the CLB logic after configuration is completed. If the BSCAN symbol is not placed in the design, all boundary scan functions are inhibited once configuration is completed, and these pins become user-programmable I/O. In this case, they must be called out by special library elements. To use these pins, place the library components TDI, TCK, and TMS instead of the usual pad symbols. Input or output buffers must still be used.
HDC	O	I/O	High During Configuration (HDC) is driven High until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, HDC is a user-programmable I/O pin.
$\overline{\text{LDC}}$	O	I/O	Low During Configuration ($\overline{\text{LDC}}$) is driven Low until the I/O go active. It is available as a control output indicating that configuration is not yet completed. After configuration, $\overline{\text{LDC}}$ is a user-programmable I/O pin.
$\overline{\text{INIT}}$	I/O	I/O	Before and during configuration, $\overline{\text{INIT}}$ is a bidirectional signal. A 1 kΩ to 10 kΩ external pull-up resistor is recommended. As an active Low open-drain output, $\overline{\text{INIT}}$ is held Low during the power stabilization and internal clearing of the configuration memory. As an active Low input, it can be used to hold the FPGA in the internal WAIT state before the start of configuration. Master mode devices stay in a WAIT state an additional 30 to 300 µs after $\overline{\text{INIT}}$ has gone High. During configuration, a Low on this output indicates that a configuration data error has occurred. After the I/O go active, $\overline{\text{INIT}}$ is a user-programmable I/O pin.
PGCK1 - PGCK4 (Spartan)	Weak Pull-up	I or I/O	Four Primary Global inputs each drive a dedicated internal global net with short delay and minimal skew. If not used to drive a global buffer, any of these pins is a user-programmable I/O. The PGCK1-PGCK4 pins drive the four Primary Global Buffers. Any input pad symbol connected directly to the input of a BUFGP symbol is automatically placed on one of these pins.

Device-Specific Pinout Tables

Device-specific tables include all packages for each Spartan and Spartan-XL device. They follow the pad locations around the die, and include boundary scan register locations.

Some Spartan-XL devices are available in Pb-free package options. The Pb-free package options have the same pinouts as the standard package options.

XCS05 and XCS05XL Device Pinouts

XCS05/XL Pad Name	PC84(4)	VQ100	Bndry Scan
VCC	P2	P89	-
I/O	P3	P90	32
I/O	P4	P91	35
I/O	-	P92	38
I/O	-	P93	41
I/O	P5	P94	44
I/O	P6	P95	47
I/O	P7	P96	50
I/O	P8	P97	53
I/O	P9	P98	56
I/O, SGCK1(1), GCK8(2)	P10	P99	59
VCC	P11	P100	-
GND	P12	P1	-
I/O, PGCK1(1), GCK1(2)	P13	P2	62
I/O	P14	P3	65
I/O, TDI	P15	P4	68
I/O, TCK	P16	P5	71
I/O, TMS	P17	P6	74
I/O	P18	P7	77
I/O	-	P8	83
I/O	P19	P9	86
I/O	P20	P10	89
GND	P21	P11	-
VCC	P22	P12	-
I/O	P23	P13	92
I/O	P24	P14	95
I/O	-	P15	98
I/O	P25	P16	104
I/O	P26	P17	107
I/O	P27	P18	110
I/O	-	P19	113
I/O	P28	P20	116
I/O, SGCK2(1), GCK2(2)	P29	P21	119
Not Connected(1), M1(2)	P30	P22	122
GND	P31	P23	-
MODE(1), M0 (2)	P32	P24	125
VCC	P33	P25	-

XCS05 and XCS05XL Device Pinouts

XCS05/XL Pad Name	PC84(4)	VQ100	Bndry Scan
Not Connected(1), $\overline{\text{PWRDWN}}$(2)	P34	P26	126(1)
I/O, PGCK2(1), GCK3 (2)	P35	P27	127(3)
I/O (HDC)	P36	P28	130(3)
I/O	-	P29	133(3)
I/O ($\overline{\text{LDC}}$)	P37	P30	136(3)
I/O	P38	P31	139(3)
I/O	P39	P32	142(3)
I/O	-	P33	145(3)
I/O	-	P34	148(3)
I/O	P40	P35	151(3)
I/O ($\overline{\text{INIT}}$)	P41	P36	154(3)
VCC	P42	P37	-
GND	P43	P38	-
I/O	P44	P39	157(3)
I/O	P45	P40	160(3)
I/O	-	P41	163(3)
I/O	-	P42	166(3)
I/O	P46	P43	169(3)
I/O	P47	P44	172(3)
I/O	P48	P45	175(3)
I/O	P49	P46	178(3)
I/O	P50	P47	181(3)
I/O, SGCK3(1), GCK4(2)	P51	P48	184(3)
GND	P52	P49	-
DONE	P53	P50	-
VCC	P54	P51	-
$\overline{\text{PROGRAM}}$	P55	P52	-
I/O (D7(2))	P56	P53	187(3)
I/O, PGCK3(1), GCK5(2)	P57	P54	190(3)
I/O (D6(2))	P58	P55	193(3)
I/O	-	P56	196(3)
I/O (D5(2))	P59	P57	199(3)
I/O	P60	P58	202(3)
I/O	-	P59	205(3)
I/O	-	P60	208(3)
I/O (D4(2))	P61	P61	211(3)
I/O	P62	P62	214(3)
VCC	P63	P63	-
GND	P64	P64	-
I/O (D3(2))	P65	P65	217(3)
I/O	P66	P66	220(3)
I/O	-	P67	223(3)
I/O (D2(2))	P67	P68	229(3)
I/O	P68	P69	232(3)
I/O (D1(2))	P69	P70	235(3)

XCS10 and XCS10XL Device Pinouts

XCS10/XL Pad Name	PC84[4]	VQ100	CS144[2,4]	TQ144	Bndry Scan
I/O	P80	P81	A10	P116	17
GND	-	-	C9	P118	-
I/O	-	-	B9	P119	20
I/O	-	-	A9	P120	23
I/O	P81	P82	D8	P121	26
I/O	P82	P83	C8	P122	29
I/O	-	P84	B8	P123	32
I/O	-	P85	A8	P124	35
I/O	P83	P86	B7	P125	38
I/O	P84	P87	A7	P126	41
GND	P1	P88	C7	P127	-

Notes:

1. 5V Spartan family only
2. 3V Spartan-XL family only
3. The “PWRDWN” on the XCS10XL is not part of the Boundary Scan chain. For the XCS10XL, subtract 1 from all Boundary Scan numbers from GCK3 on (175 and higher).
4. PC84 and CS144 packages discontinued by PDN2004-01

Additional XCS10/XL Package Pins

TQ144					
Not Connected Pins					
P117	-	-	-	-	-
5/5/97					

CS144					
Not Connected Pins					
D9	-	-	-	-	-
4/28/99					

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144[2,4]	TQ144	PQ208	Bndry Scan
VCC	P89	D7	P128	P183	-
I/O	P90	A6	P129	P184	62
I/O	P91	B6	P130	P185	65
I/O	P92	C6	P131	P186	68
I/O	P93	D6	P132	P187	71
I/O	-	-	-	P188	74
I/O	-	-	-	P189	77
I/O	P94	A5	P133	P190	80
I/O	P95	B5	P134	P191	83
VCC[2]	-	-	-	P192	-
I/O	-	C5	P135	P193	86
I/O	-	D5	P136	P194	89
GND	-	A4	P137	P195	-
I/O	-	-	-	P196	92
I/O	-	-	-	P197	95
I/O	-	-	-	P198	98
I/O	-	-	-	P199	101
I/O	P96	B4	P138	P200	104
I/O	P97	C4	P139	P201	107
I/O	-	A3	P140	P204	110
I/O	-	B3	P141	P205	113
I/O	P98	C3	P142	P206	116

XCS20 and XCS20XL Device Pinouts

XCS20/XL Pad Name	VQ100	CS144[2,4]	TQ144	PQ208	Bndry Scan
I/O, SGCK1[1], GCK8[2]	P99	A2	P143	P207	119
VCC	P100	B2	P144	P208	-
GND	P1	A1	P1	P1	-
I/O, PGCK1[1], GCK1[2]	P2	B1	P2	P2	122
I/O	P3	C2	P3	P3	125
I/O	-	C1	P4	P4	128
I/O	-	D4	P5	P5	131
I/O, TDI	P4	D3	P6	P6	134
I/O, TCK	P5	D2	P7	P7	137
I/O	-	-	-	P8	140
I/O	-	-	-	P9	143
I/O	-	-	-	P10	146
I/O	-	-	-	P11	149
GND	-	D1	P8	P13	-
I/O	-	E4	P9	P14	152
I/O	-	E3	P10	P15	155
I/O, TMS	P6	E2	P11	P16	158
I/O	P7	E1	P12	P17	161
VCC[2]	-	-	-	P18	-
I/O	-	-	-	P19	164
I/O	-	-	-	P20	167

XCS30 and XCS30XL Device Pinouts *(Continued)*

XCS30/XL Pad Name	VQ100[5]	TQ144	PQ208	PQ240	BG256[5]	CS280[2,5]	Bndry Scan
I/O	P18	P28	P44	P52	V1	T1	272
I/O	P19	P29	P45	P53	T4	T2	275
I/O	-	P30	P46	P54	U3	T3	278
I/O	-	P31	P47	P55	V2	U1	281
I/O	P20	P32	P48	P56	W1	V1	284
I/O, SGCK2[1], GCK2[2]	P21	P33	P49	P57	V3	U2	287
Not Connected[1], M1[2]	P22	P34	P50	P58	W2	V2	290
GND	P23	P35	P51	P59	GND[4]	GND[4]	-
MODE[1], M0[2]	P24	P36	P52	P60	Y1	W1	293
VCC	P25	P37	P53	P61	VCC[4]	U3	-
Not Connected [1], $\overline{\text{PWRDWN}}$[2]	P26	P38	P54	P62	W3	V3	294 [1]
I/O, PGCK2[1], GCK3[2]	P27	P39	P55	P63	Y2	W2	295 [3]
I/O (HDC)	P28	P40	P56	P64	W4	W3	298 [3]
I/O	-	P41	P57	P65	V4	T4	301 [3]
I/O	-	P42	P58	P66	U5	U4	304 [3]
I/O	P29	P43	P59	P67	Y3	V4	307 [3]
I/O ($\overline{\text{LDC}}$)	P30	P44	P60	P68	Y4	W4	310 [3]
I/O	-	-	P61	P69	V5	T5	313 [3]
I/O	-	-	P62	P70	W5	W5	316 [3]
I/O	-	-	P63	P71	Y5	R6	319 [3]
I/O	-	-	P64	P72	V6	U6	322 [3]
I/O	-	-	P65	P73	W6	V6	325 [3]
I/O	-	-	-	P74	Y6	T6	328 [3]
GND	-	P45	P66	P75	GND[4]	GND[4]	-
I/O	-	P46	P67	P76	W7	W6	331 [3]
I/O	-	P47	P68	P77	Y7	U7	334 [3]
I/O	P31	P48	P69	P78	V8	V7	337 [3]
I/O	P32	P49	P70	P79	W8	W7	340 [3]
VCC	-	-	P71	P80	VCC[4]	T7	-
I/O	-	-	P72	P81	Y8	W8	343 [3]
I/O	-	-	P73	P82	U9	U8	346 [3]
I/O	-	-	-	P84	Y9	W9	349 [3]
I/O	-	-	-	P85	W10	V9	352 [3]
I/O	P33	P50	P74	P86	V10	U9	355 [3]
I/O	P34	P51	P75	P87	Y10	T9	358 [3]
I/O	P35	P52	P76	P88	Y11	W10	361 [3]
I/O ($\overline{\text{INIT}}$)	P36	P53	P77	P89	W11	V10	364 [3]
VCC	P37	P54	P78	P90	VCC[4]	U10	-
GND	P38	P55	P79	P91	GND[4]	GND[4]	-
I/O	P39	P56	P80	P92	V11	T10	367 [3]
I/O	P40	P57	P81	P93	U11	R10	370 [3]
I/O	P41	P58	P82	P94	Y12	W11	373 [3]
I/O	P42	P59	P83	P95	W12	V11	376 [3]
I/O	-	-	P84	P96	V12	U11	379 [3]